Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/705,627	CHOU, WEN SAN
Examiner	Art Unit
Patrick Hamo	3746

	SEARCHED				
Class	Subclass	Date	Examiner		
417	415	11/15/2006	PH		
			:		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

DATE	EXMR
/15/2006	PH